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Contents

∨ii ix	Authors Conference Committee
SESSION 1	THIN FILM MATERIALS I
11064 02	Influence of transition layer on the surface scattering of unmodified silicon carbide [11064-55]
SESSION 2	TECHNOLOGY OF THIN FILMS I
11064 03	Thickness dependence of Cr-doped VO $_2$ thin films deposition by reactive pulsed magnetron sputtering [11064-45]
SESSION 4	TECHNOLOGY OF THIN FILMS II
11064 04	Preparation of silica thin film by hot pressing process for passive radiative cooling [11064-22]
SESSION 5	THIN FILM MATERIALS II
11064 05	Optical functions of fishnet metamaterial embedded in dielectrics [11064-54]
11064 06	Optical and electrical characteristics of radio frequency sputtered ITO and In-free transparent conductors (Invited Paper) [11064-6]
11064 07	Investigation on tuning of WS ₂ /SiC band gap with an external electric field [11064-17]
11064 08	Enhance anti-water ability of high transmittance film in mid-infrared band [11064-14]
11064 09	Performance of a spectral beam combining grating with YAG substrate [11064-48]
SESSION 6	APPLICATION OF THIN FILMS I
11064 0A	Efficient broadband light absorption enhancement in InP/ZnO core-shell nanocone arrays for photovoltaic application [11064-11]

SESSION 7	PHYSICS OF THIN FILMS II
11064 OB	Energy flow difference structure design based on micro hemisphere structure [11064-23]
11064 0C	A lift-off of pattern structures on the heat-mode resists [11064-19]
11064 0D	Positive and negative properties of laser heat-mode resists [11064-33]
SESSION 8	APPLICATION OF THIN FILMS II
11064 OE	Wide-incident angle and low polarization aberration edge filter [11064-24]
11064 OF	Subwavelength periodic nanostructures fabricated by femtosecond laser in metal, dielectric and metal-dielectric-metal coating [11064-53]
	POSTER SESSION 11064
11064 0G	Employing Ni-Cr co-doping to prepare low phase transition temperature VO ₂ film [11064-57]
11064 OH	Annealing effects on optical and structural properties of TiO_2 thin films deposited by ion beam sputtering [11064-18]
11064 01	Broadband chirped volume Bragg grating for one-hundred-femtosecond pulse compression [11064-50]
11064 OJ	Broadband polarization beam splitter based on subwavelength grating in Terahertz [11064-5]
11064 OK	Comparison of mechanical properties evolution of polyimide films in space radiation environment [11064-4]
11064 OL	Correlation between the structure and laser damage properties of ion assisted HfO_2 thin films [11064-12]
11064 OM	Design and fabrication of antireflective surface microstructures on lithium triborate [11064-51]
11064 ON	Design of linear polarizer in 3-13µm broad infrared region with multilayer nanostructures [11064-30]
11064 00	Effect of MgF ₂ deposition temperature on AI mirrors in vacuum ultraviolet [11064-42]
11064 OP	Effect of temperature on optical properties of CeO _x film being irradiated by Co 60 prepared by RF magnetron sputtering [11064-8]
11064 0Q	Effects of different oxygen flow on refractive index and absorption characteristics of Ta_2O_5 film [11064-37]

11064 OR	Efficient method for determination of laser conditions adopted in laser-induced micro-lithology based on laser polymerization size analysis [11064-34]
11064 OS	Electrical property of OSR second surface mirror in space radiation environments [11064-3]
11064 OT	Experimental observation and numerical analysis for dynamical output in free-running multi-longitudinal mode erbium doped fiber ring laser [11064-15]
11064 OU	Green vegetables derived simultaneously carbon dots as sensitizer and carbon particles as counter electrode for dye-sensitized solar cells [11064-26]
11064 OV	Improvement on fluorescent properties of photonic crystals filled by quantum dots based on multi-layer films [11064-2]
11064 OW	Oblique incidence reflectance of resonators based on suspended two-dimensional membranes [11064-40]
11064 OX	Optical design of perovskite/silicon laminated solar cells based on grating structure [11064-58]
11064 OY	Optimization of morphology and electrochemical characteristics of nickel film by sputtering pressure [11064-38]
11064 OZ	Photoelectric properties of transparent conductive metal mesh films based on crack template and its application in Perovskite solar cells [11064-46]
11064 10	Preparation and physical properties of germanium thin films [11064-25]
11064 11	Research on the time and mechanism of laser-induced air plasmas ignition [11064-36]
11064 13	Study on band gap and dispersion model of Al $_2$ O $_3$ thin films with different oxygen flow rates by ion beam sputtering [11064-32]
11064 14	Study on preparation process and shielding effectiveness of graphene films [11064-35]
11064 15	Annealing effects on the optical and structural properties of Y_2O_3 thin films deposited by thermal evaporation technique [11064-29]
11064 16	Development of transparent oxide thin films for flexible devices [11064-21]
11064 17	Influence of deposition temperature and precursor pulse time on properties of SiO ₂ , HfO ₂ monolayers deposited by PEALD [11064-39]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Bai, Yunli, 02 Cao, Hongchao, 09, 0M Cao, Zhen, OF Chen, Dan, 0H, 13, 15 Chen, Fengnan, 0W Chen, Guodong, 0C, 0D Chen, Junming, 09 Chen, Peng, 09, 01 Cheng, Yuyang, 0J Dai, Huifana, 01 Fan, Ping, 03, 0G Fan, Xiaochun, OB Fu, Bo, OP Fu, Haiyan, OZ Fu, Xiuhua, 08 Gao, Enlei, 0X Grilli, Maria Luisa, 06, 0F Guan, Huan, 03, 0G Guo, Mena, 10 He, Donabina, 01 He, Hongbo, 0F, 0M, 10 He, Qicong, 0G He, Shikun, 0E

Huang, Lu, 0V Huang, Ping, 0U, 0Y Huang, Qiaolin, 0E Huang, Ying, 0G Huo, Tonglin, 0O Ji, Yiqin, 0Q Jiang, Chenghui, 0Q Jiang, Kai, 16

Hu, Guohana, 05, 0F

Jiang, Yugang, 0H, 0Q, 13, 15 Jin, Jingcheng, 0G Jin, Yunxia, 09, 0I, 0M Kong, Fanyu, 09, 0I, 0M Kong, Weijin, 0J Kuang, Yawei, 0X Li, Caiyu, 0J Li, Cheng, 0R Li, Dawei, 0R Li, Shida, 0H, 0Q, 13, 15

Li, Shuangying, 00 Li, Xiao, 0K Li, Yuanjie, 16 Liu, Chen, 0Y Liu, Dandan, 13 Liu, Dengwu, 04 Liu, Hai, 0T Liu, Hao, OL

Liu, Huasong, 0H, 0Q, 13, 15

Liu, Shijie, OK Lu, Heng, OW Lu, Jun, OW

Luo, Yongping, OU, OY, OZ

Ma, Hao, OR
Ma, Xiaofeng, OS
Ma, Yuke, O7
Mao, Wenjing, OW
Meng, Qingfei, OV
Moser, Joel, OW
Ou, Hui, OZ
Pan, Feng, OL
Piegari, Angela, OF
Qin, Xuefei, OA

Shao, Jianda, 09, 0F, 0R, 0S, 10, 17

Shao, Shuying, 10 Shao, Yuchen, 0R Shen, Zicai, 0K, 0S Shi, Kai, 14 Shi, Kailiang, 0B Shi, Weimin, 0V Song, Chen, 17 Su, Junhong, 11, 14 Sun, Wenci, 16 Sun, Yong, 0M

Sytchkova, Anna, 05, 0F

Tang, Kai, OT Wan, Lin, OW Wang, Chinhua, ON Wang, Fengli, OO Wang, Gang, 02, 0E Wang, Guixia, 11 Wang, Hong, 16 Wang, Hui, OP Wang, Jie, 16 Wang, Li, 02, 0E Wang, Linjun, OV

Wang, Lishuan, 0H, 0Q, 13, 15 Wang, Yang, 0C, 0D

Wang, Yanzhi, 17 Wang, Yonglu, 09, 0M Wang, Zhanshan, 0O Wang, Zhengwei, 0C, 0D Wei, Jingsong, 0C, 0D Wei, Yaowei, 0L Wu, Yonggang, 0A

Xia, Jie, 0N

Xia, Zhilin, 04, 0B

Xia, Zihuan, 0A

Xiang, Zaikui, OP

Xiao, Pengda, 0X

Xiao, Yanping, 0T

Xiao, Zonghu, OU, OZ, OY

Xu, Jiao, 09

Xu, Nuo, 17

Xu, Shunjian, OU, OY, OZ

Xu, Xian'gang, 07

Xue, Dongbai, 15

Yan, Rongrong, 14

Yan, Ying, 0W

Yang, Chen, 0W

Yang, Xiao, 15

Yang, Yu, 0G

Yi, Kui, 10, 17

Yin, Chaoyi, 17

Yuan, Zhihao, ON

Zeng, Tingting, 17

Zhang, Dongping, 03, 0G

Zhang, Fei, OL

Zhang, Gong, 08

Zhang, Jiyou, 02, 0E

Zhang, Kaixin, OF

Zhang, Kui, OC, OD

Zhang, Kun, OJ

Zhang, Meng, 0U

Zhang, PuHeng, OT

Zhang, Yelan, 0J

Zhang, Yibin, 09, 01, 0M

Zhang, Zhenfei, 04

Zhang, Zhuangzhuang, 0O

Zhang, Zongyi, 0A

Zhao, Jianle, 14

Zhao, Jingyin, Ol

Zhao, Yuan'an, OF, OR, 17

Zheng, Hao, 0X

Zheng, Xinyu, 0X

Zhong, Wei, OU, OY, OZ

Zhou, Hongjun, 0O

Zhou, Jian, 0A

Zhou, Xin, 14

Zhou, Yuming, 02, 0E

Zhu, Meiping, 0H, 0Q, 0S, 13, 15, 17

Zhu, Yitai, 0X

Zhu, Yubin, 0V

viii

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